

CLAIMS

1. An apparatus for debugging an imaging device,
comprising:

an image view display for qualitatively displaying pixel
characteristics in a first range of the imaging device; and

a code view display for quantitatively displaying
numerical or symbolic data of individual pixels in a second
range that is smaller than said first range and designated
within an area displayed by said image view display.

2. A semiconductor testing apparatus for testing an
imaging device, comprising:

a test head for reading an output signal from an imaging
device under test;

a memory which stores output data from said test head;
and

an image processor which processes the output data
stored in said memory;

wherein said image processor comprising:

a display unit for displaying data stored in said
memory;

an input device which receives an operator's
command;

wherein said image processor processes data stored

in said memory means based on an operator's command received from said input device;

wherein said image processor comprises an image view display for qualitatively displaying pixel characteristics in a first range of the imaging device on said display unit according to an operator's command, and a code view display for quantitatively displaying on said display unit numerical or symbolic data of individual pixels in a second range that is smaller than said first range and designated in an area displayed by said image view display;

whereby data with respect to the pixel characteristics of the imaging device can be displayed by said image view display or said code view display or both.

3. A semiconductor testing apparatus according to claim 2, wherein said image view display comprises an image view, and an area display that indicates on the image view a code display area of the code view.

4. A semiconductor testing apparatus according to claim 2, wherein said code view display comprises a code view and a coordinate display for displaying the coordinates of data located at a central position in said code view display.

5. A semiconductor testing apparatus according to claim

2, wherein said code view displaying means comprises a code view and a marker display for indicating data shown at a central position in said code view display.

6. A method of testing an imaging device, comprising the steps of:

retrieving output data from the imaging device as digital data;

qualitatively displaying the digital data as an image view in a first range of the imaging device;

accepting the designation of a second range that is smaller than said first range in the image view, which qualitatively displays digital data; and

quantitatively displaying characteristics of pixels in the imaging device within said second range with numerical or symbolic codes.

7. A method according to claim 6, wherein the step of retrieving output data from the imaging device comprises the step of processing the retrieved digital data.

8. A computer-readable recording medium storing a program for enabling a computer to function as:

an image view display for qualitatively displaying pixel characteristics in a first range of an imaging device; and

a code view display for quantitatively displaying numerical or symbolic data of individual pixels in a second range that is smaller than said first range and designated within an area displayed by said image view display.

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